Special Issue

Advances in Middle Infrared (Mid-IR) Lasers and Their Application: 2nd Edition

Message from the Guest Editors

In the past twenty years, there has been a growing interest in middle infrared (mid-IR) lasers and their applications, which has benefited from the development of laser technology and laser gain medium, including solid-state laser material and fiber. Moreover, these works have promoted the development of related technical applications such as sensing, remote sensing, high-resolution spectroscopy, and so on. This Special Issue of the journal *Applied Sciences* aims to focus on the most recent advancements in mid-IR lasers, from materials to laser sources, and their applications in spectroscopy, trace gas detection, remote sensing, optical microscopy, biomedicine, etc. We will welcome submissions of both original research and review papers.

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multidimensional network.

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